



AF/IFW

In the United States Patent and Trademark Office

Serial Number: 10/772,053
Appn. Filed: 02/03/04
Applicant: Guobiao Zhang
Appn. Title: Three-Dimensional-Memory-Based Self-Test
Integrated Circuits and Methods
Examiner/GAU: Pham, Long/2814

Mailed: Sep. 5, 2006

AMENDMENT UNDER RULE 116

Commissioner of Patents and Trademarks
P.O. Box 1450
Alexandria, VA 22313-1450

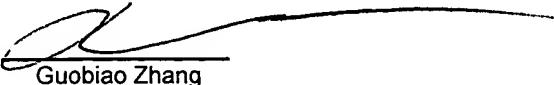
Sir:

In response to the Office Action mailed June 8, 2006, Applicant requests that the above application be amended as follows (over):

Date of the deposit Sep. 5, 2006

I certify that this paper is being deposited with the United States Postal Service using "First Class Mail" under 37 CFR 1.10 on the date indicated above and is addressed to "Box Non-Fee Amendments, Commissioner of Patents and Trademarks, Alexandria, VA 22313-1450."

Signed:



Guobiao Zhang